

“Metallic Magnetic Calorimeters: Micromachined Absorbers for Cosmic Microwave Background Radiation”.



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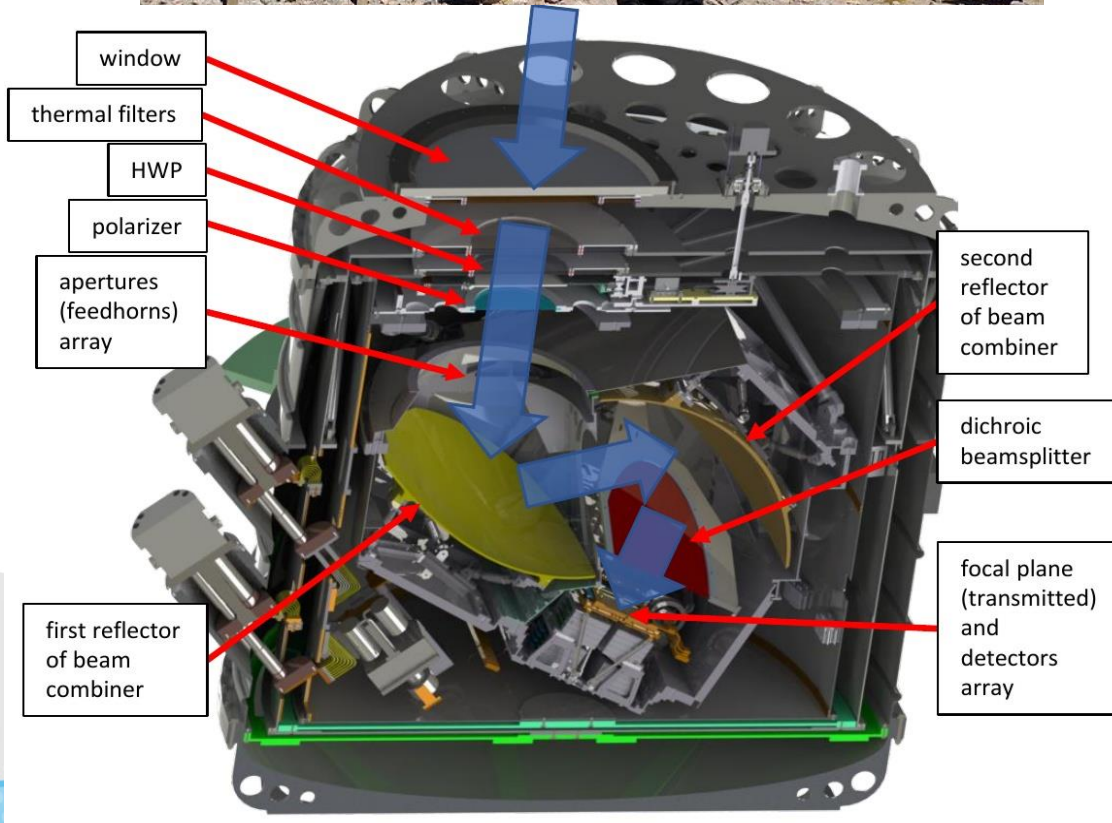
Prof. Dr. Marc Weber

Institute for Data Processing and Electronics
Karlsruhe Institute of Technology, ALEMANIA





Motivation: QUBIC radiotelescope



APC Paris, France
C2N Orsay, France
CSNSM Orsay, France
IAS Orsay, France
IRAP Toulouse, France
LAL Orsay, France
Universita di Milano-Bicocca, Italy
Universita degli studi di Milano, Italy
Universita La Sapienza, Roma, Italy
Maynooth University, Ireland
Cardiff University, UK
University of Manchester, UK
Brown University, USA
Richmond University, USA
University of Wisconsin, USA
Centro Atómico Constituyentes, Argentina
GEMA, Argentina
Comisión Nacional de Energía Atómica, Argentina
Facultad de Cs Astronómicas y Geofísicas, Argentina
Centro Atómico Bariloche and Instituto Balseiro, Argentina
Instituto de Tecnologías en Detección y Astroparticulas, Argentina
Instituto Argentino de Radioastronomía, Argentina

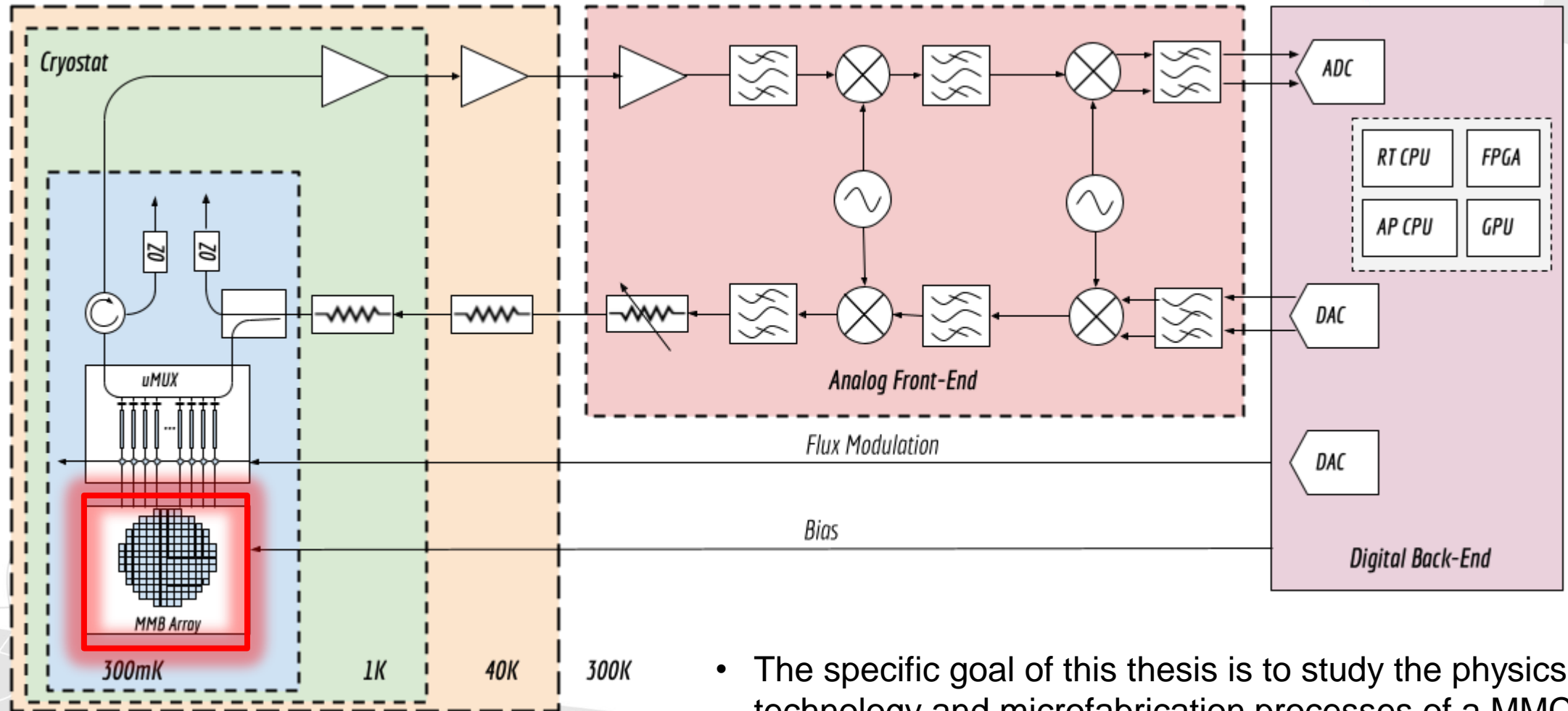
130 Collaborators
22 Laboratories
6 countries

+SISSA Joined



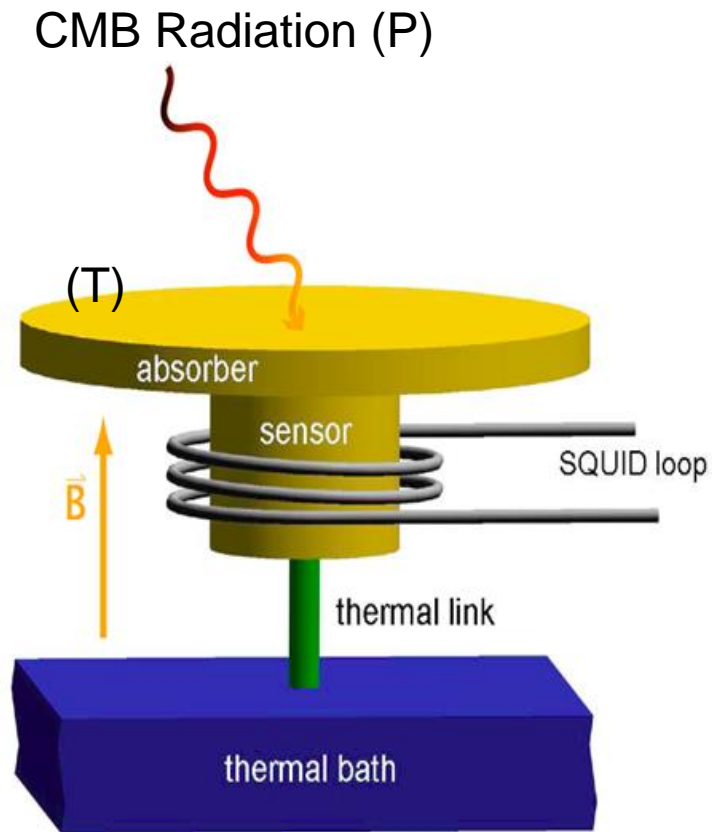


Detection and front-end



- The specific goal of this thesis is to study the physics, technology and microfabrication processes of a MMC sensor, in particular its energy conversion layers.

MAGNETIC METALLIC BOLOMETERS (MMB)



$$\Delta P \rightarrow \nabla T \rightarrow \nabla \Phi \rightarrow \nabla \Phi_S$$

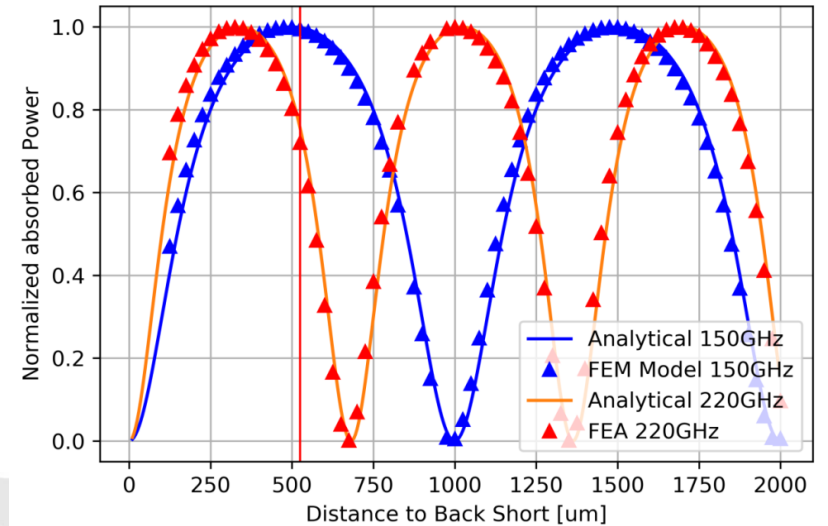
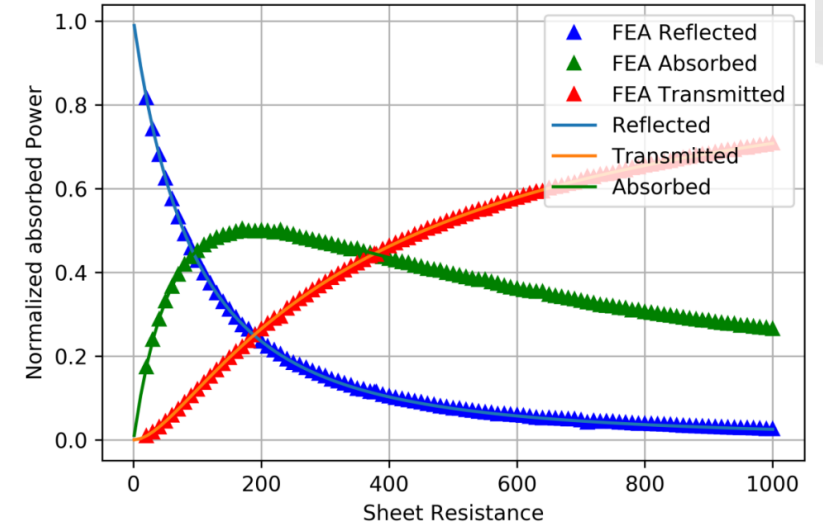
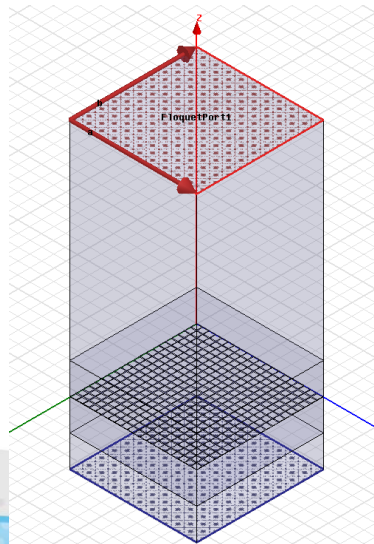
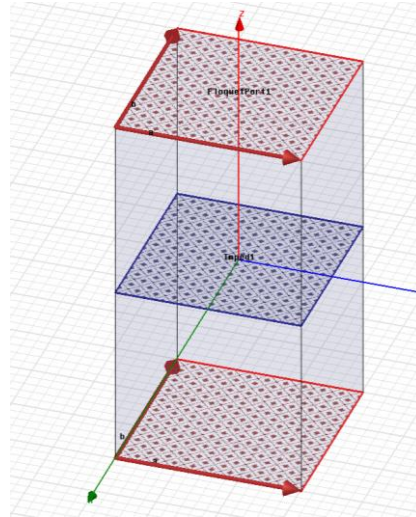
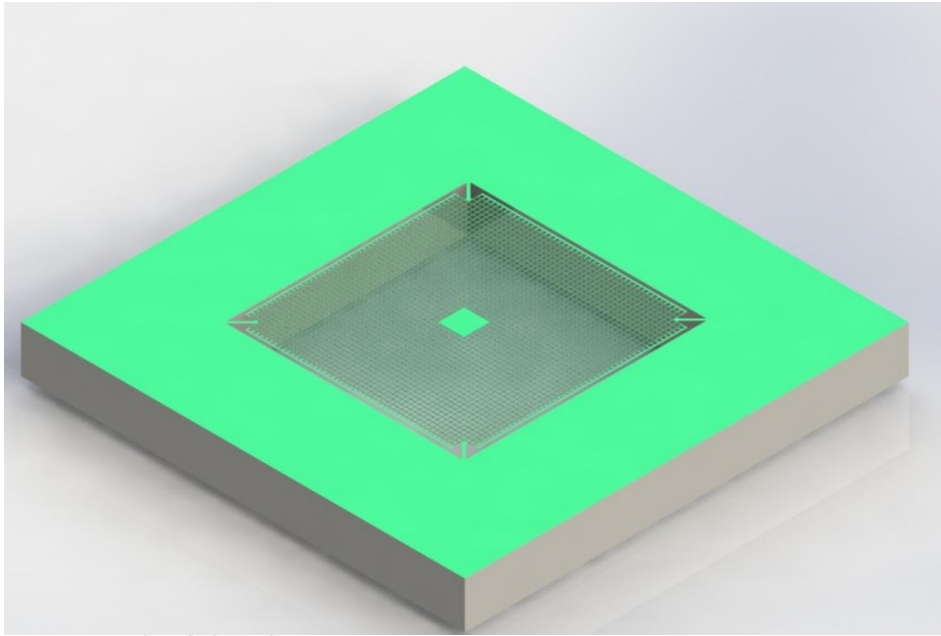
$$\mathfrak{R}_{MMB} = \frac{\partial \Phi_S}{\partial P} = \frac{\partial T}{\partial P} \frac{\partial \Phi}{\partial T} \frac{\partial \Phi_S}{\partial \Phi}$$



$$NEP = 5 \cdot 10^{-17} \text{ W} \cdot \text{Hz}^{-0.5}$$

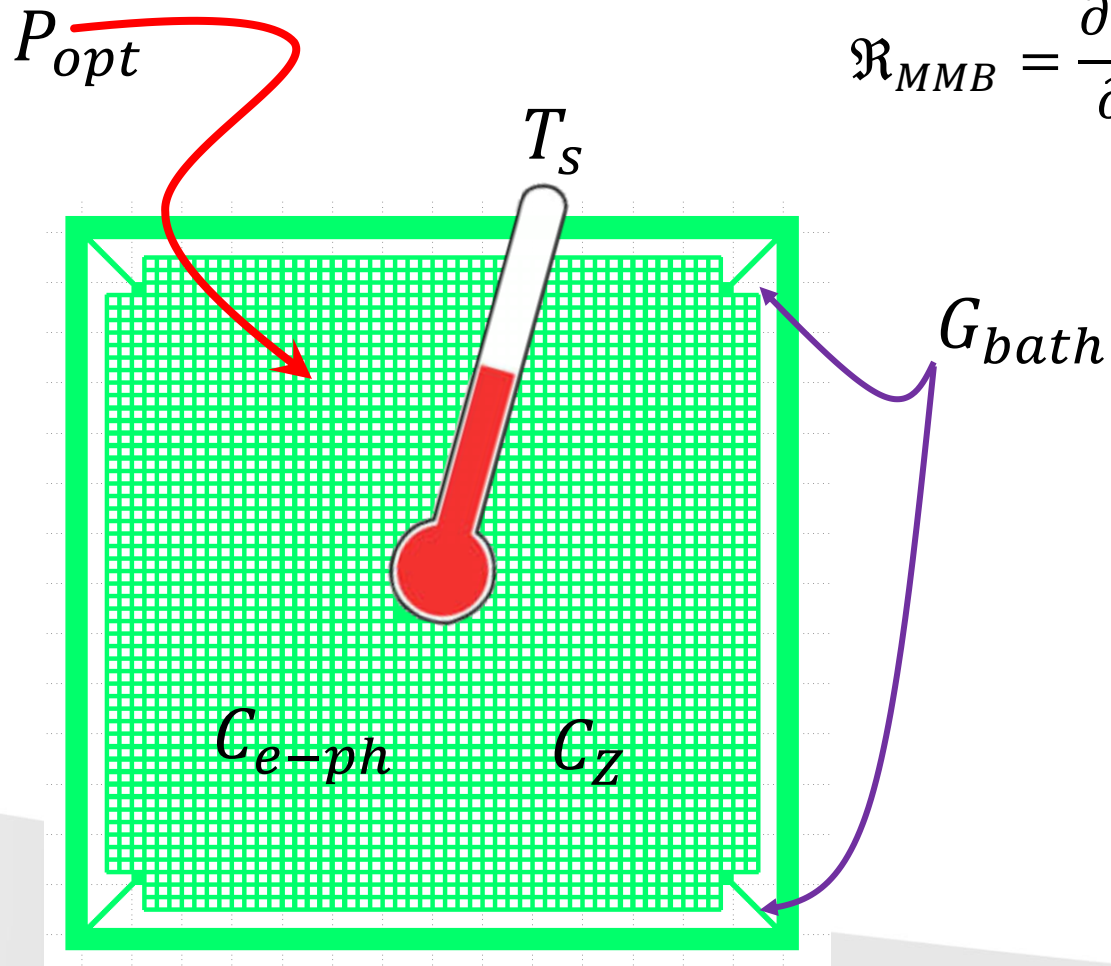
MAGNETIC METALLIC BOLOMETERS

Absorbing models

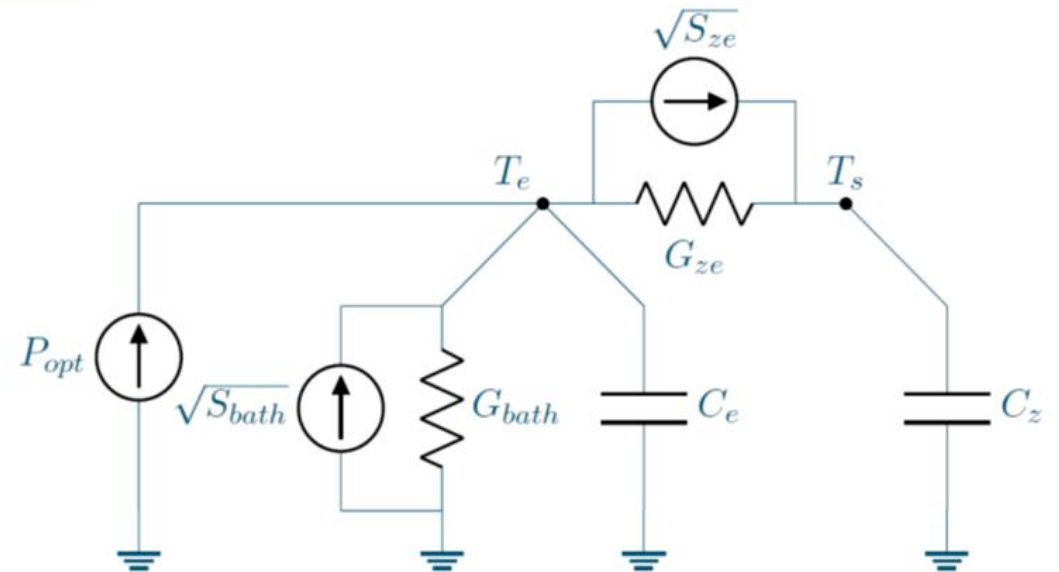


MAGNETIC METALLIC BOLOMETERS

Thermal models



$$\mathfrak{R}_{MMB} = \frac{\partial \Phi_S}{\partial P} = \frac{\partial T}{\partial P} \frac{\partial \Phi}{\partial T} \frac{\partial \Phi_S}{\partial \Phi}$$



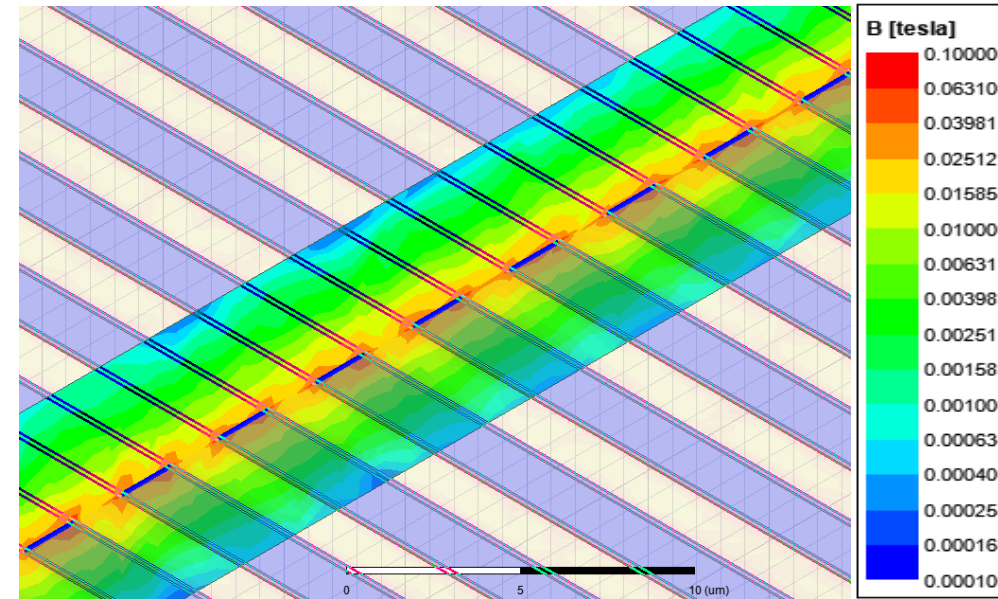
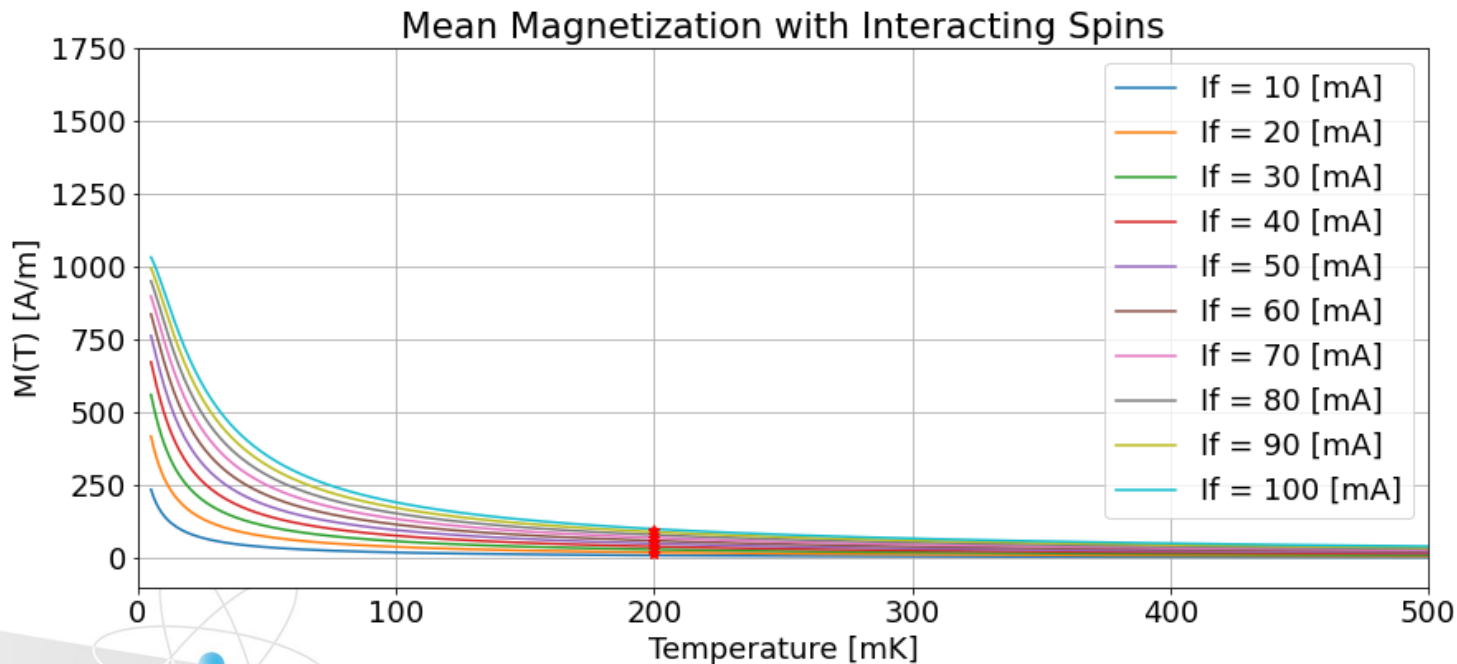
$$\frac{\partial T}{\partial P} = \frac{1}{G_{bath}} \cdot \frac{1}{\frac{C_e + C_z}{G_{bath} G_{ze}} \cdot s^2 + \frac{C_z (G_{bath} + G_{ze}) + C_e G_{ze}}{G_{bath} G_{ze}} \cdot s + 1}$$

MAGNETIC METALLIC BOLOMETERS

Temperature dependant magnetization



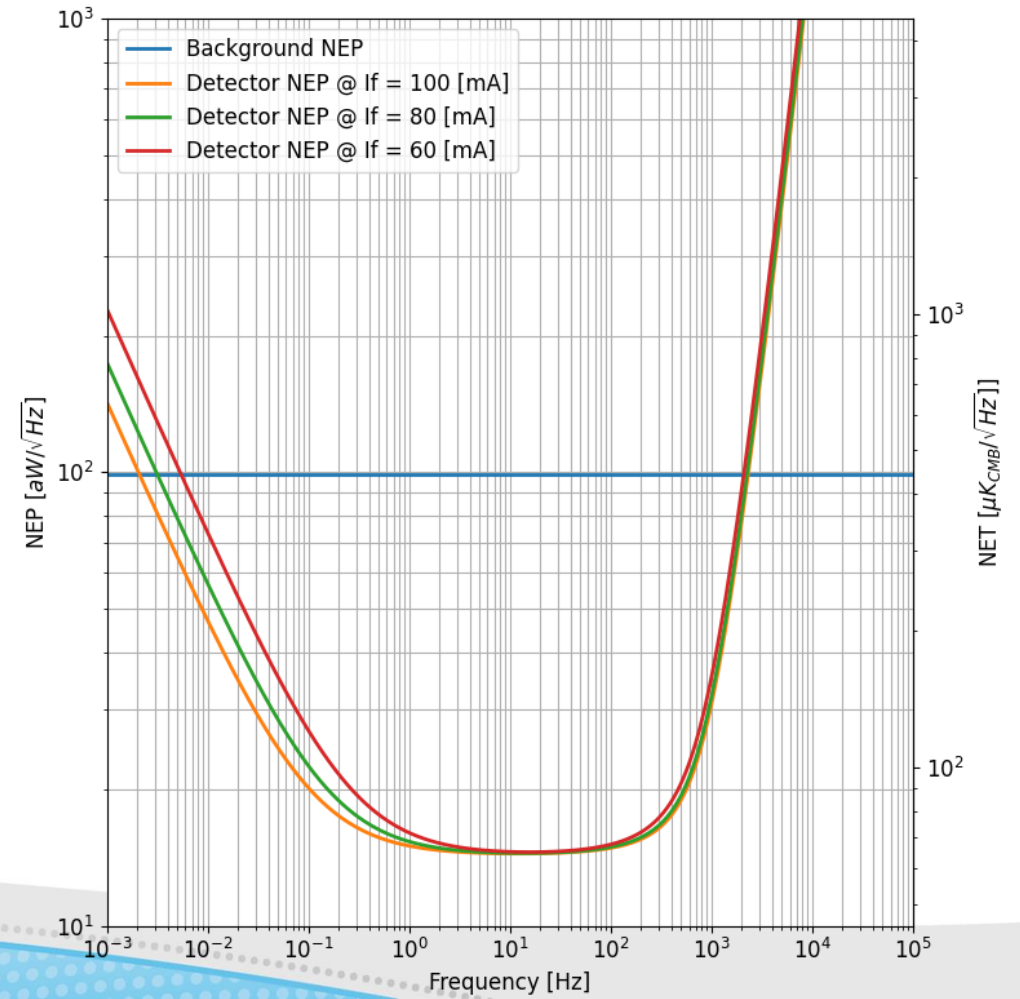
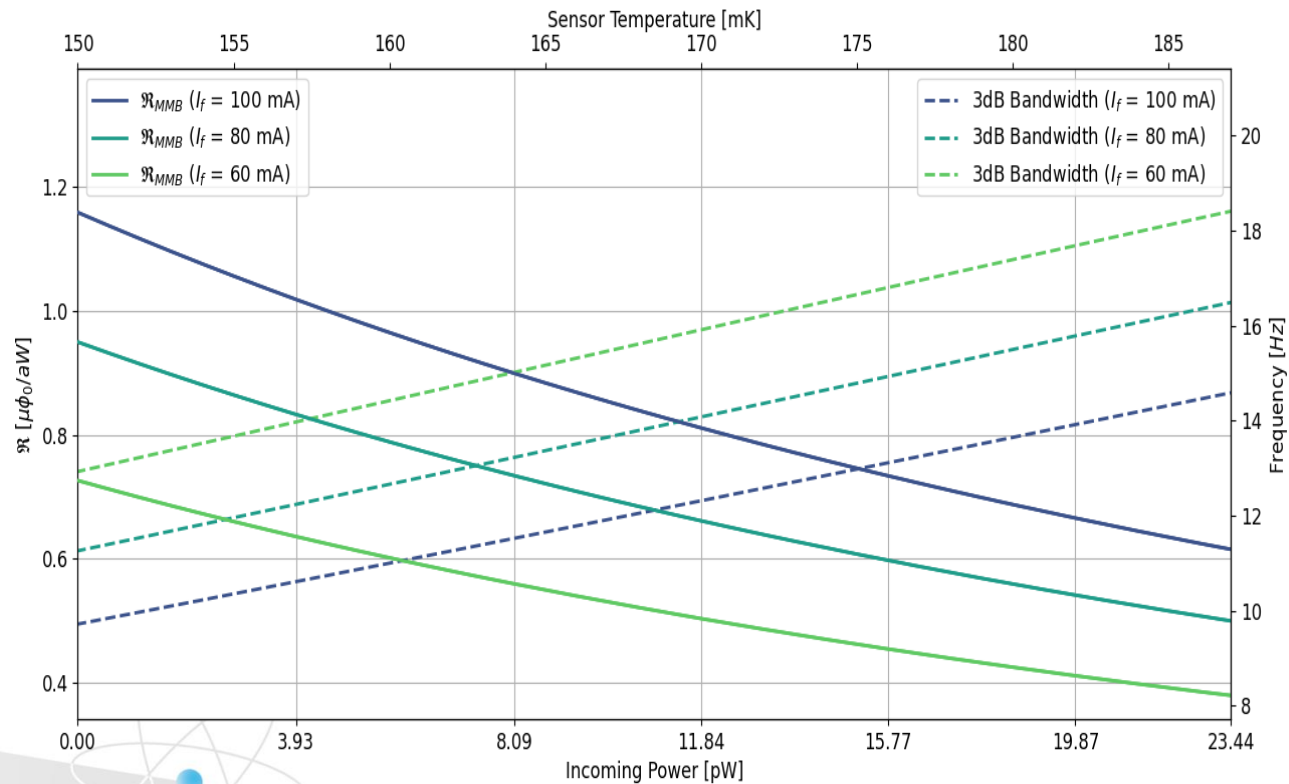
$$\mathfrak{R}_{MMB} = \frac{\partial \Phi_S}{\partial P} = \frac{\partial T}{\partial P} \frac{\partial \Phi}{\partial T} \frac{\partial \Phi_S}{\partial \Phi}$$



$$\mathfrak{R}_{MMB} = \frac{1}{G_{bath}} \cdot \sum \frac{|\vec{B}(\vec{r})|}{I_{coil}} \cdot \left. \frac{\partial M}{\partial T} \right|_{|\vec{B}(\vec{r})|} \cdot \Delta V \cdot \frac{k\sqrt{L_{in}L_s}}{L_s + 2(L_{stray} + L_{in})}$$

MAGNETIC METALLIC BOLOMETERS

Responsivity and noise



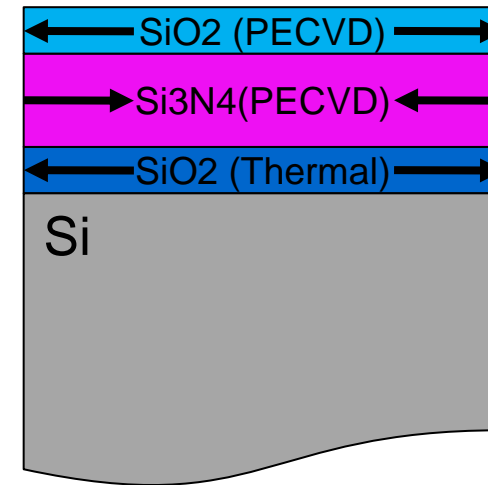
MAGNETIC METALLIC BOLOMETERS

Absorber fabrication



Constrains:

- Only with available equipment.
 - Fluorine(SF₆, C₄F₈) chemistry for membrane release.
 - No Si₃N₄ exposed to etch.
 - High density
 - Yield >90%
- Keep cost as low as possible

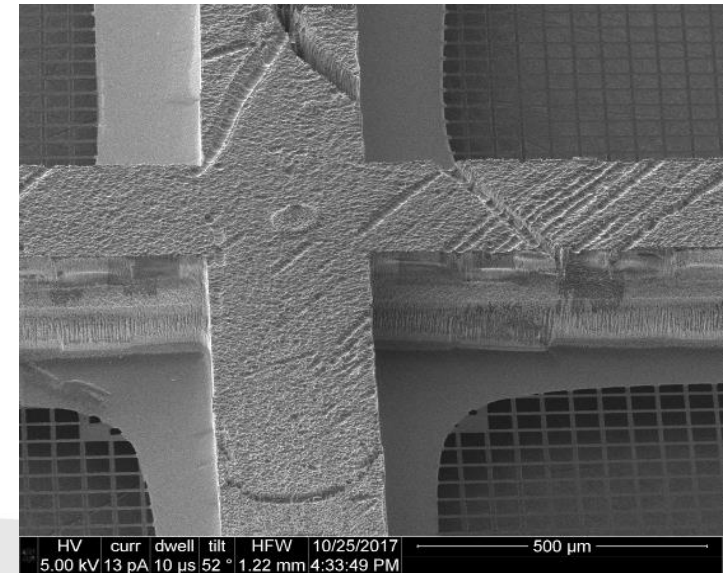
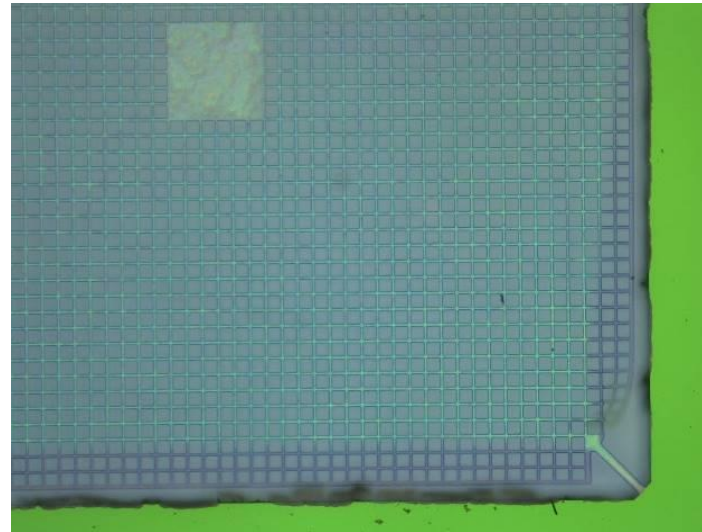
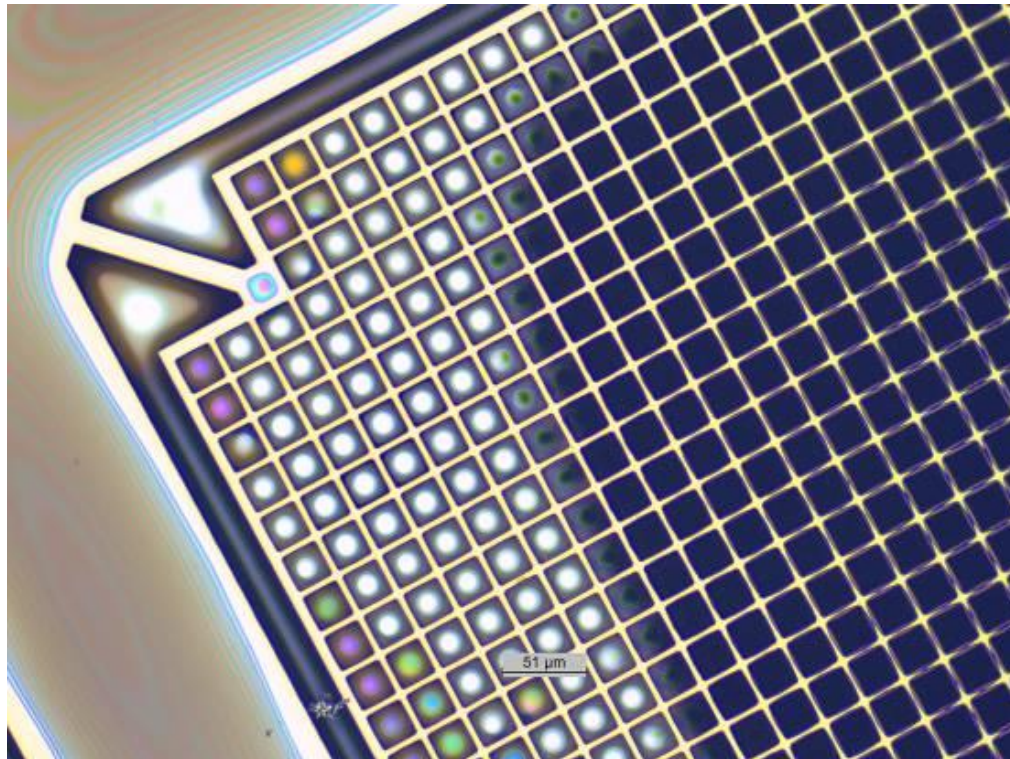


Results

| | |
|-----------------------|-------------|
| Stress Type: | Compression |
| Average Stress (MPa): | 9.1 |
| Center Stress (MPa): | 7.6 |

MAGNETIC METALLIC BOLOMETERS

Absorber fabrication



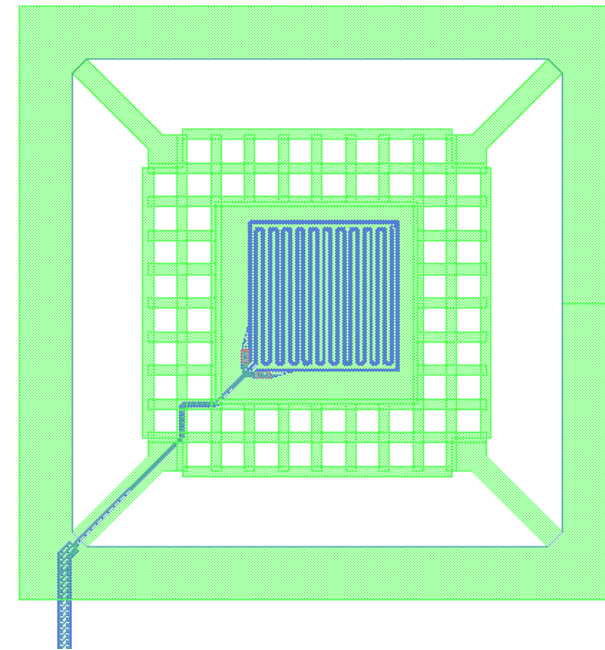
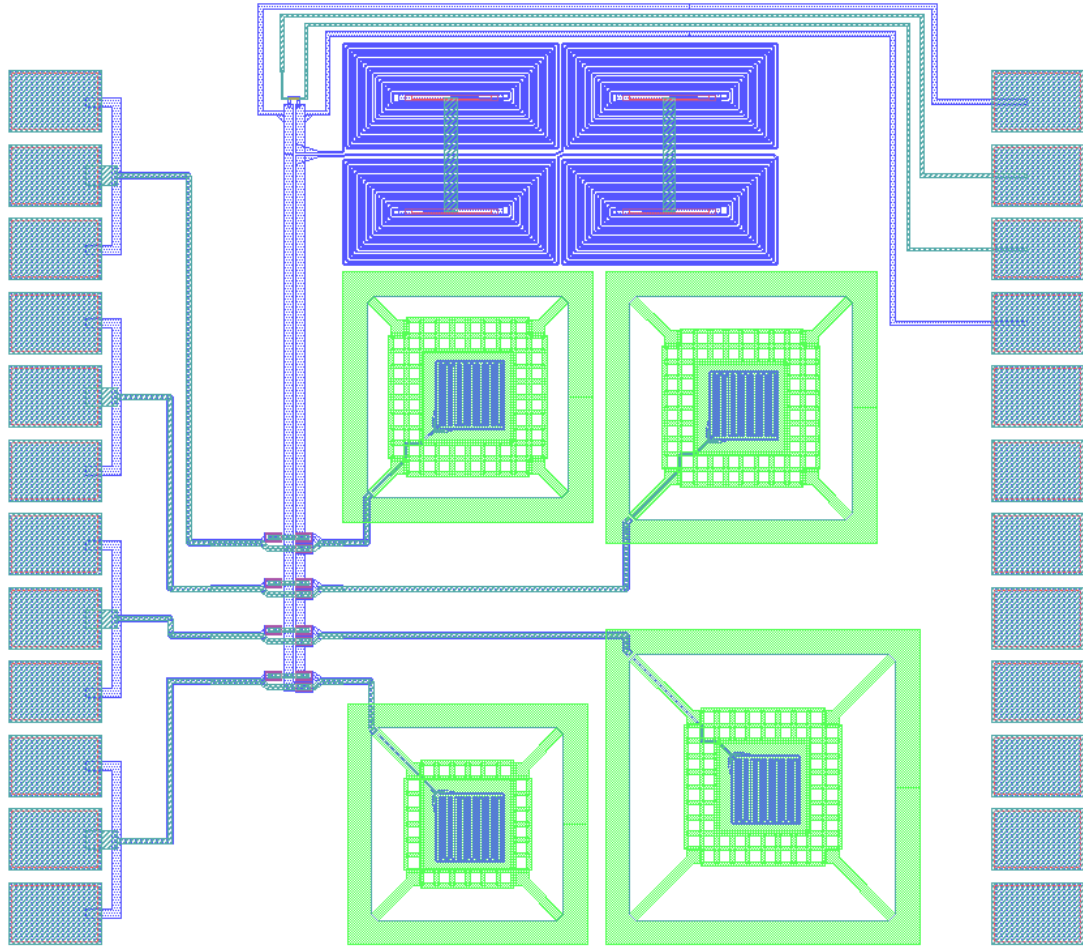
- High density
- Yield >90%



New process
coming soon!

MAGNETIC METALLIC BOLOMETERS

First designs for the C and G determination



MAGNETIC METALLIC BOLOMETERS

Facilities up-grade



35m² added to cleanroom



New 6 guns AJA ACT2400 sputter tool for superconducting films deposition. PO Sept. 2021. expected to arrive in Jun. 2022



New Blufors LD450 DR PO June. 2021. expected to arrive in Ago. 2022

MAGNETIC METALLIC BOLOMETERS

Ongoing and future work



Ongoing

- New membrane release process
- Masks design for first prototypes and C - G determination experiment.

Future

- Fabricate and measure first sensor prototypes
- Set up superconducting film deposition processes and sensor characterization at mK in CNEA-CAC.
- Enhance KIT-CNEA cooperation in cryogenic quantum detectors microfabrication.

Thanks!



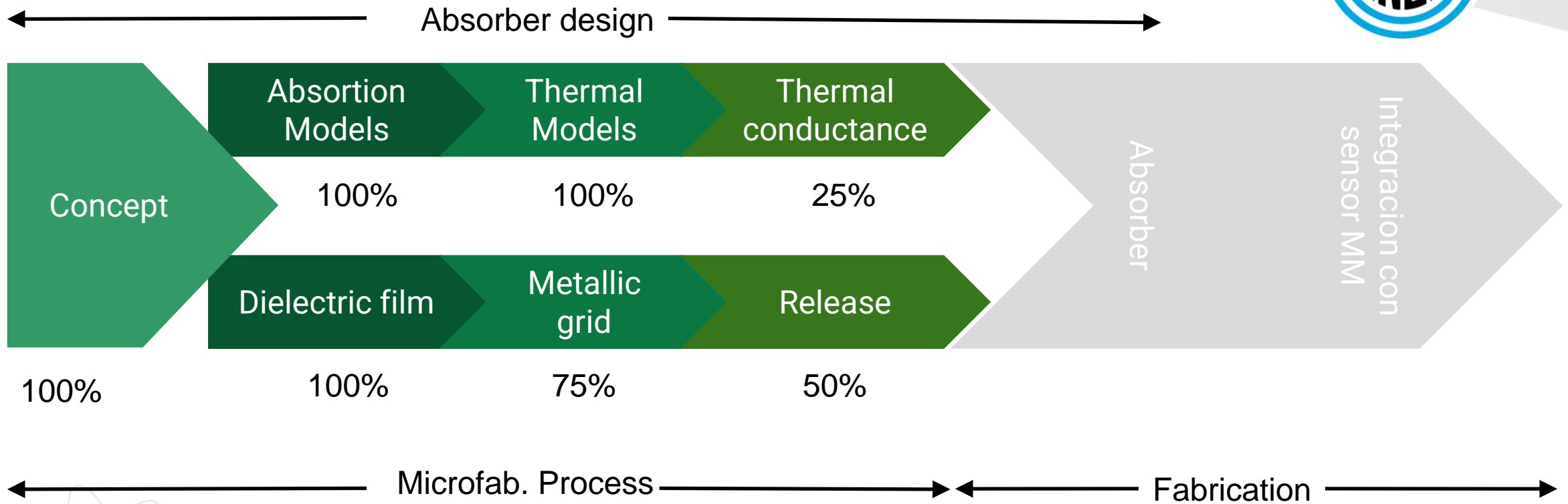
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Ing. Juan Salum

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Mg. Ing Alejandro Fasciswski
Dr. Matias Wegner
Ing. Andres Didonato
Ing. Claudio Ferrari
Ms. Diego Perez Gagni
Tec. Dante Mercado
Tec. Diego Silva



Advance



100%

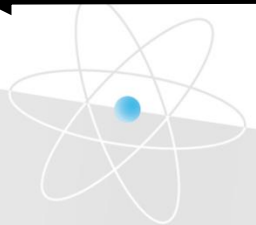
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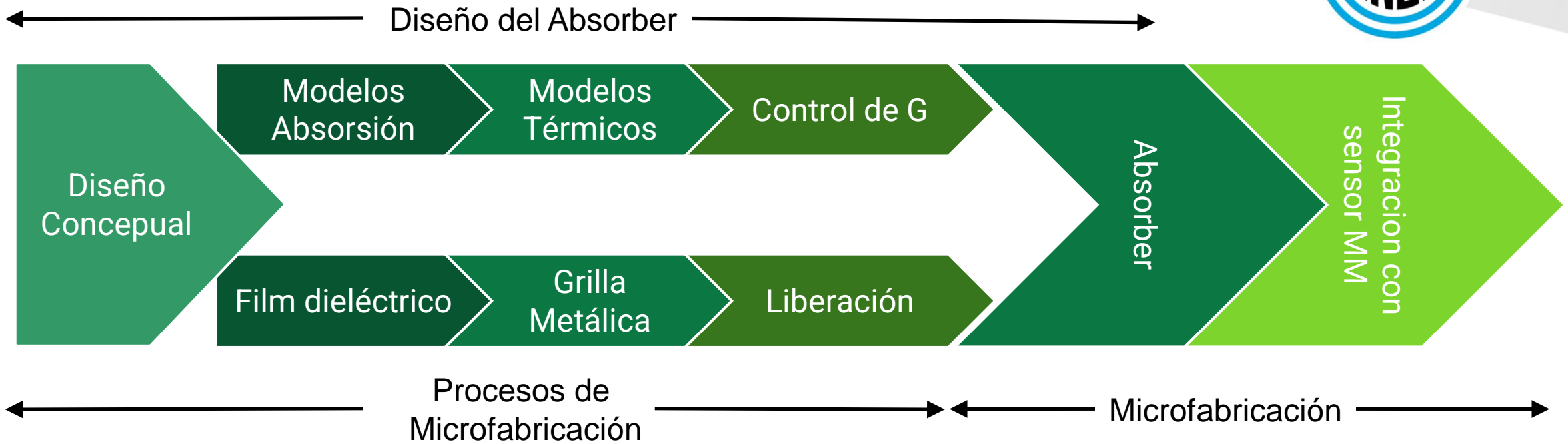
50%

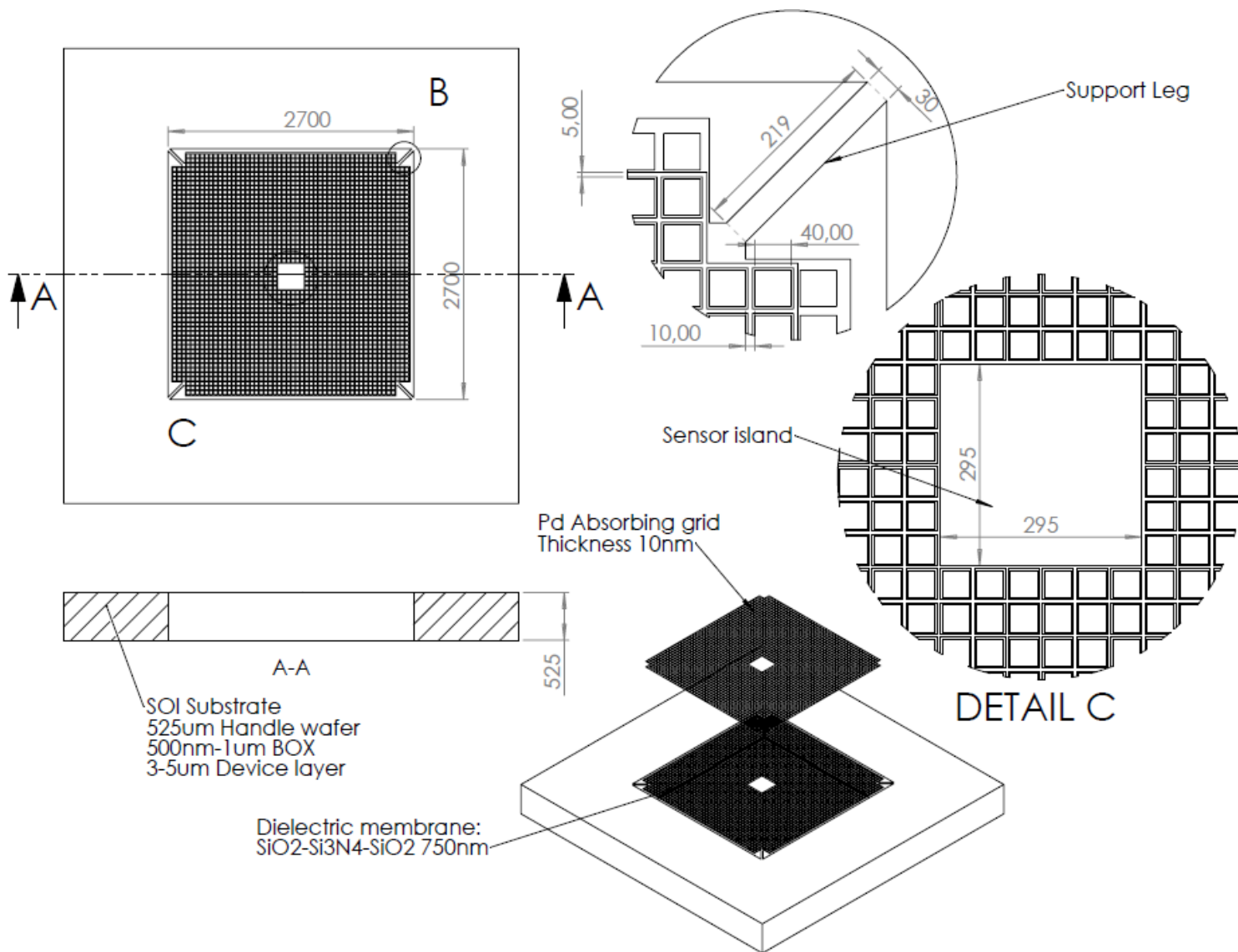
Microfab. Process

Fabrication



DESARROLLO





$$G_{bath} = \frac{\partial P}{\partial T} = N \cdot \frac{A l S}{3 Leg_L} \cdot \left(\frac{a}{4} \cdot T_s + \frac{b}{16} \cdot T_s^3 \right)$$

Donde A es el área transversal de la barra de soporte.

Leg_L largo de la barra y l es el camino libre medio de los fonones a la temperatura de trabajo. a y b son parámetros experimentales

BACKUP

**CNEA´s Micro and Nanotechnology Department:
Located at Centro Atómico Constituyentes, Buenos Aires.**



Composed by :

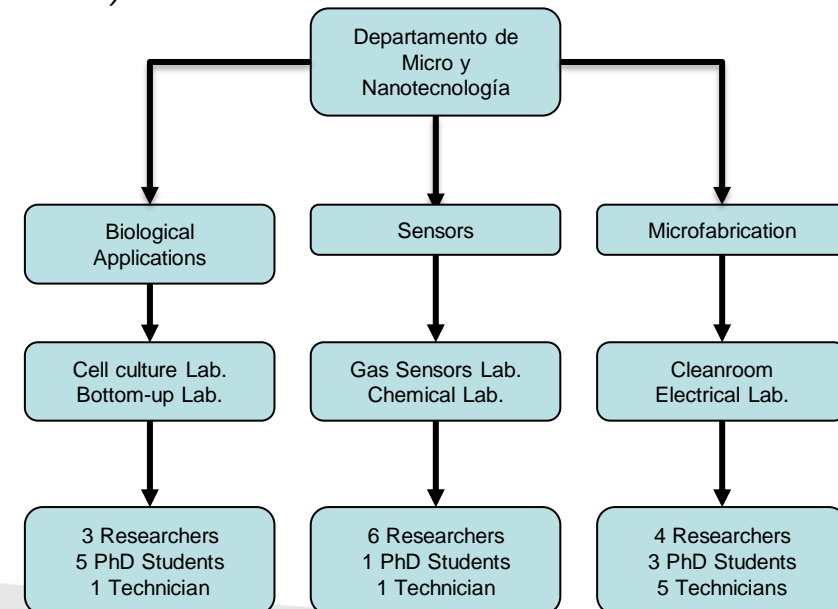
- 3 divisions: Sensors, Biology Applications, Microfabrication
- 13 researchers (CNEA permanent staff + CONICET researchers)
- 9 PhD. Students
- 7 Specialized Technicians.

Facilities:

- 5 application Labs for Cell culture, Gas Sensors, Electrical Characterization, Bottom-up and chemical.
- 135 sqr. mts ISO 6 and 7 cleanroom (40 sqr.m to be added in 2020)

Projects:

- Pressure sensors for harsh environments
- Microfluidic devices for gas separation
- Environmental gas sensors
- Lab-on-a-chip detectors for endemic diseases
- TES detectors for CMB research
- AlGaN devices for radiation detection, and uwave devices



BACKUP CLEANROOM I

Clean room

135m² facility operated and maintained by a highly qualified technical staff open to CNEA's and general scientific community.

Statistics (Dic. 2018)

Projects:20

Users: 46

Total cleanroom usage: ~4600hs./yr.



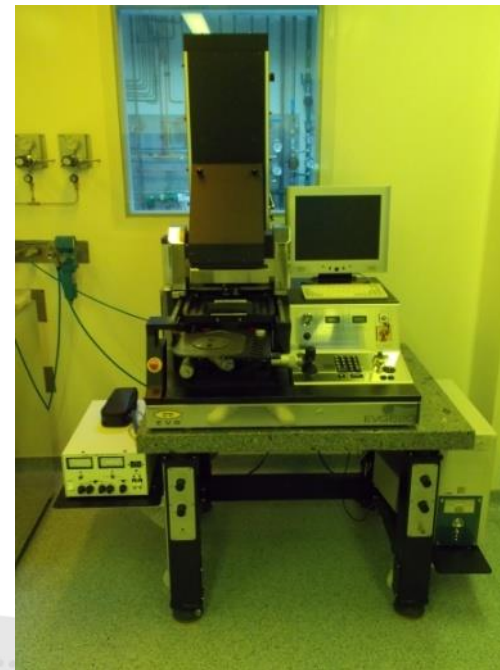
BACKUP CLEANROOM II



| Lithography | | |
|-------------|--|-------------------|
| ID | Name | Ubicación |
| L-01 | EVG 620 Mask aligner / Wafer Aligner | Sala Litografía |
| L-02 | EVG 501 wafer bonder | Sala Litografía |
| L-03 | Litho Bench | Sala Litografía |
| L-04 | HEIDELBERG Instruments DWL66fs Mask writer | Sala Masterizador |



Generador de Máscaras [HEIDELBERG](#) DWL66fs



EVG 620 Mask Aligner



EVG 501 Wafer Bonder



BACKUP CLEANROOM II



| Deposition | | |
|------------|--|----------------------------|
| ID | Nombre | Ubicación |
| D-01 | Sputtering AJA Orion | Sala de Ataques por Plasma |
| D-02 | PECVD ADVANCED VACUUM VISION 310 | Sala de Ataques por Plasma |
| D-03 | Electroplating Cell SEMCOM 1000 | Sala Ataques Químicos |
| D-04 | UNIVEX 350 E-beam + thermal evaporator | LAB C301 |



Sputtering AJA Orion



PECVD Vision 310



Electroplating Cell SEMCOM 1000



BACKUP CLEANROOM II



| Etching | | |
|---------|--|----------------------------|
| ID | Nombre | Ubicación |
| A-01 | RIE OXFORD INSTRUMENTS PLASMALAB80+ | Sala de Ataques por Plasma |
| A-02 | D-RIE OXFORD INSTRUMENTS PLASMAPRO COBRA | Sala de Ataques por Plasma |
| A-03 | Oxigen plasma asher SPEC AURA1000 | Sala de Ataques por Plasma |
| A-04 | Wet etching BenchAMERIMADE | Sala Ataques Químicos |
| A-05 | Wafer cleaning bench AMERIMADE | Sala Ataques Químicos |



HEIDELBERG DWL66fs



SPEC AURA1000



PlasmaLab 80+



PlasmaLab 100



BACKUP CLEANROOM II



| Inspection | | |
|------------|--|------------|
| ID | Nombre | Ubicación |
| M-02 | Perfilómetro Óptico 3D, Veeco Wyco NT1100 | Sala Metro |
| M-03 | Perfilómetro por contacto KLA-TENCOR ALPHA STEP D120 | Sala Metro |
| M-04 | Horiba AUTO-SE Elipsometer | Sala Metro |
| M-05 | Dual Beam SEM-FIB FEI Quanta 3D 200i | Sala Metro |



SEM-FIB



Perfilómetro óptico 3D



AUTO-SE Elipsometer



BACKUP CLEANROOM II



| Auxiliary equipment | | |
|---------------------|---|----------------------------|
| ID | Nombre | Ubicación |
| DS-01 | DISCO DAD3240 dicing Saw | Lab C220 |
| DS-02 | Wire Bonder Hybond 912 | Sala de ataques por plasma |
| DS-03 | Annealsys AS-ONE Rapid thermal annealer | Sala de ataques por plasma |



Dicer Disco



Wire bonder

